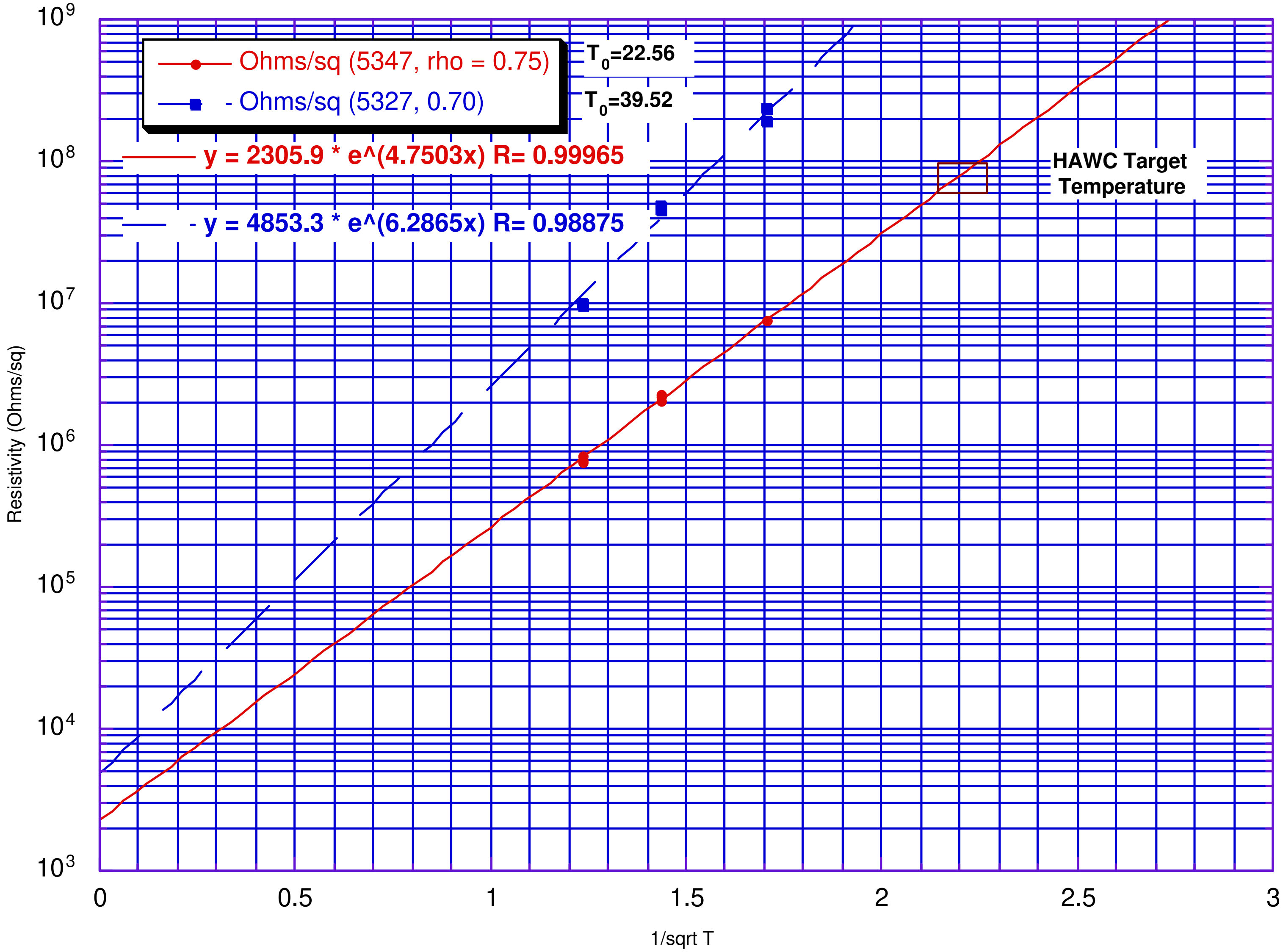Calibration Run Wafer Screening Test
Performed by D. Dowell & M. Fruend
Plotted 4/7/00